

Methods, FMF, Fiederle

<p><b>PR-Spectroscopy</b></p> <p><i>Photomodulated Reflection Spectroscopy</i></p>	<p>Model: Unit and Room: Responsible: Further information:</p>	<p><i>FMF model FMF, 1rd floor, R. 01027 Dr. M. Fiederle, 203 4775 <a href="http://www.fmf.uni-freiburg.de/service/servicegruppen/sg_matchar/chat/">www.fmf.uni-freiburg.de/service/servicegruppen/sg_matchar/chat/</a></i></p>
<p>Short Description:</p> <p>Measurement of semiconductor band structure and measurement of surface reflection and material transmission</p>	<p>Picture of the Equipment</p>	
<p>Available Experiments/Techniques:</p> <p>Excitation with LASER or LED in combination with white light reflection. Phase locked signal detection.</p>		
<p>Special Equipment:</p> <p>Lock-In Amplifier SR830 0.85m double monochromator SPEX 1404 Low temperature unit (77K - 300K) Optics, gratings, bandpass filters Si photodiode, liquid nitrogen cooled Ge photodiode Ar-ion laser Thermal white light sources</p>		
<p>Measurements on the equipment are currently done by:</p>	<p><input type="checkbox"/> Students <input type="checkbox"/> Students after Introduction <input checked="" type="checkbox"/> Students after extensive training <input checked="" type="checkbox"/> Trained scientific service personal</p>	
<p>Recent Publications, where this instrument was important (optional): Give citation</p>	<p>J. Appl. Phys. 103, 073103 (2008); doi:10.1063/1.2895002</p>	
<p>Typical problems that may be solved with this instrument:</p>	<p>- <i>Investigations on semiconductor band structure</i> - <i>Reflection / Transmission analysis</i></p>	